

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicants: Constantin Bulucea and Rebecca Rossen  
Assignee: Siliconix Incorporated  
Title: TRENCH DMOS POWER TRANSISTOR WITH FIELD-SHAPING  
PROFILE AND THREE-DIMENSIONAL GEOMETRY  
Serial No.: 08/086,976 Filed: 7/2/93  
Examiner: J. Carroll Group Art Unit: 2508  
Attorney Docket No.: M-799-2D US

San Jose, California  
March 17, 1994

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Washington, D. C. 20231

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Declaration of Constantin Bulucea

GROUP 2500

Sir:

I, Constantin Bulucea, hereby declare:

1. I am an inventor of claims 17-29 of the above-mentioned Application and inventor of the subject matter described and claimed therein (collectively, the "Subject Matter").
2. I conceived the Subject Matter prior to August 24, 1988. In support of my conception date prior to August 24, 1988, I enclose Exhibit A, which includes Figures 1-10 and 21-31A of the above-mentioned Application. Exhibit A, which shows the Subject Matter and bears the signatures of Messr. Richard K. Williams and Randolph D. Mah, are signed respectively on August 10, 1988 and August 11, 1988 in my presence.
3. Between August 11, 1988 and October 3, 1988, I worked with Mr. Lorimer K. Hill, then Patent Coordinator of Siliconix Incorporated, to obtain Siliconix's approval for an application for patent. As evidence of this effort, I enclose a letter (Exhibit B) from Mr. Hill to Mr. Paul Winters, a partner of the law firm Skjerven, Morrill, MacPherson Franklin and Friel.

LAW OFFICES OF  
SKJERVEN, MORRILL,  
MACPHERSON, FRANKLIN  
& FRIEL

25 METRO DRIVE  
SUITE 700  
SAN JOSE, CA 95110  
(408) 283-1222  
FAX (408) 283-1223

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("Skjerven Morrill"), instructing Mr. Winters to prepare an application for patent in the United States.

3. Between October 3, 1988 and December 27, 1988, I worked diligently with my attorney Mr. John F. Schipper, who was then associated with Skjerven Morrill, to prepare a patent application. The patent application became U.S. Patent Application, serial no. 07/290,546, filed on December 27, 1988, issued on December 10, 1991 as U.S. Patent 5,072,266, from which the parent Application (serial no. 07/762,103, filed on 9/18/91) of the present Application based priority under 35 U.S.C. § 120 .

4. I did not abandon the Subject Matter at any time between my conception of the Subject Matter and December 27, 1988.

Respectfully submitted,

MAR 17 1994

*Constantin Bulucea*

Constantin Bulucea

I hereby certify that this correspondence is being deposited with the United States Postal Service as first class mail in an envelope addressed to: Commissioner of Patents and Trademarks, Washington, D.C., 20231, on 3/17 1994

3/17/94  
Date of Signature

[Signature]  
Attorney for Applicant(s)

# EXHIBIT A

#6

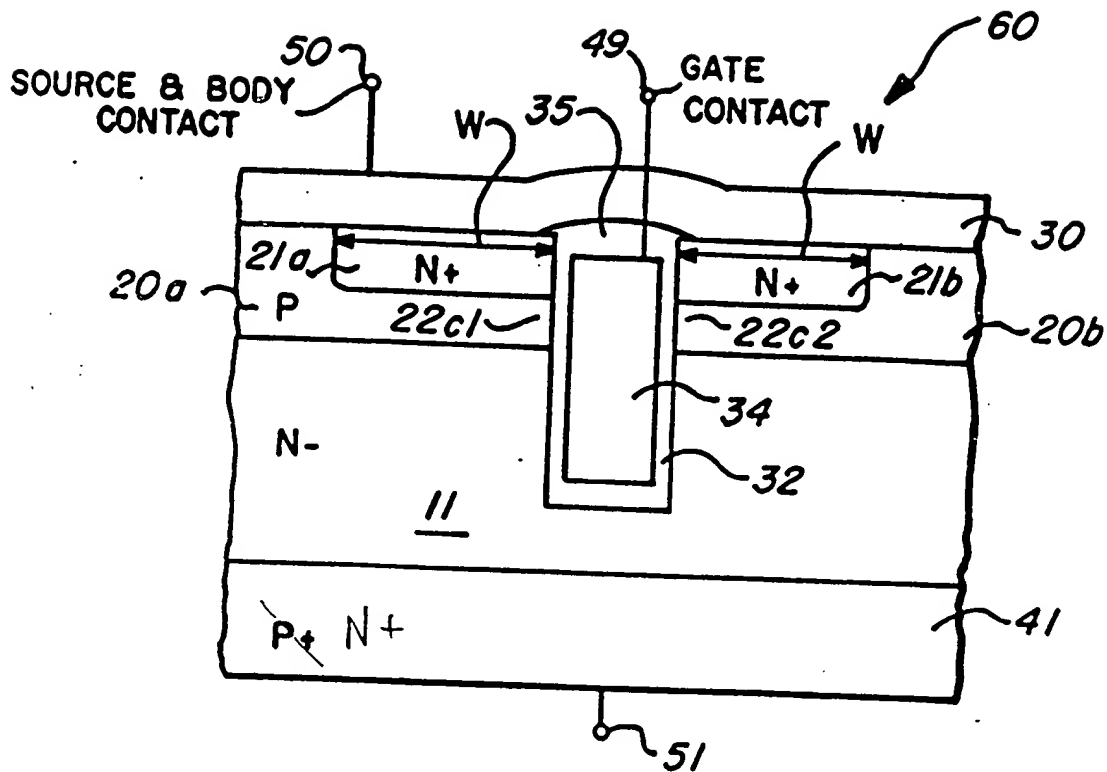


Figure 1

Cross-section of a trench DMOS power transistor cell (prior art, /1,2/).

read & understood *[Signature]* August 10, 1988  
 read and understood *Randolph D. Lech* August 11, 1988

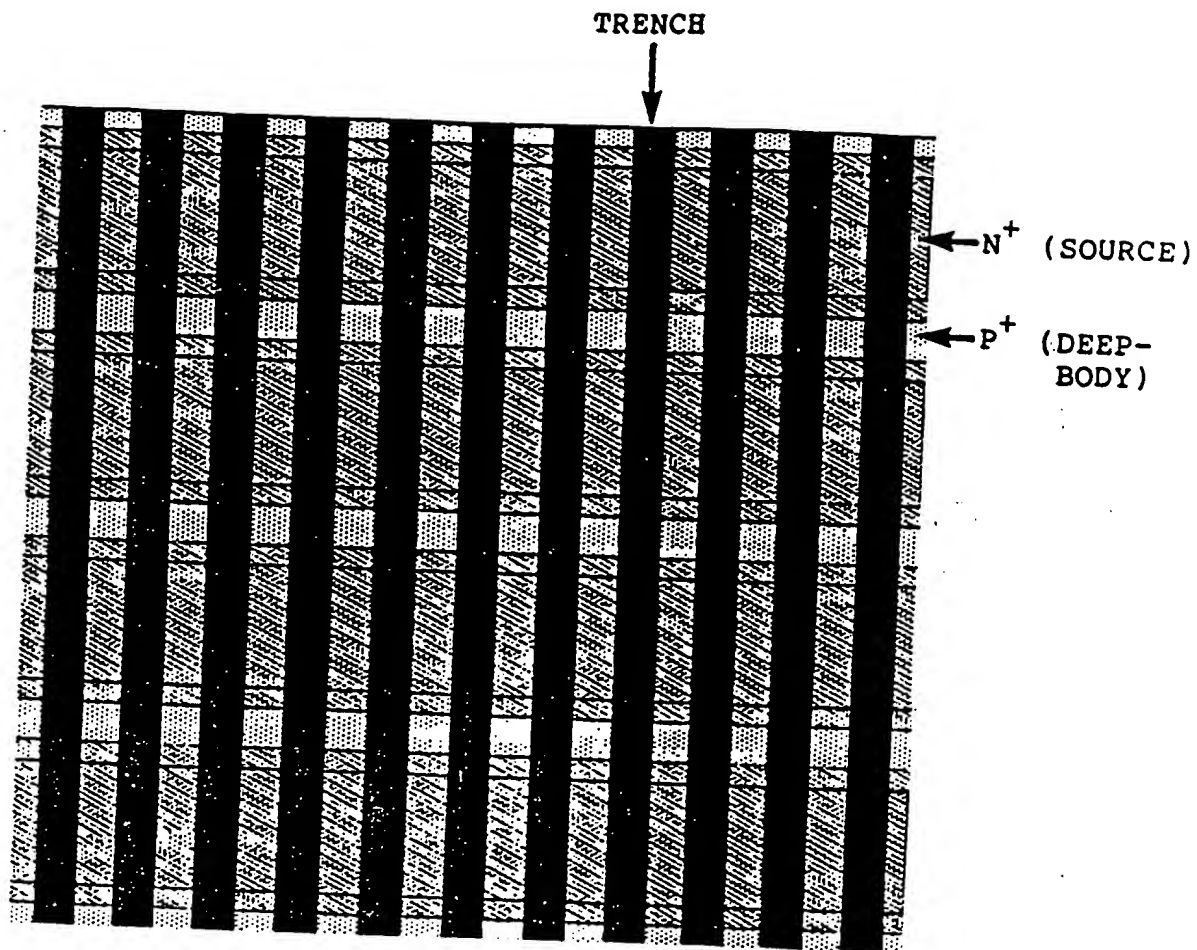


Figure 2,a

"Open-cell" implementation of a trench DMOS  
power transistor (CALMA hard copy, active region).  
Siliconix, Inc., 1987.

read + understood QXW August 10, 1988  
read and understood Randolph D. Webb August 11, 1988

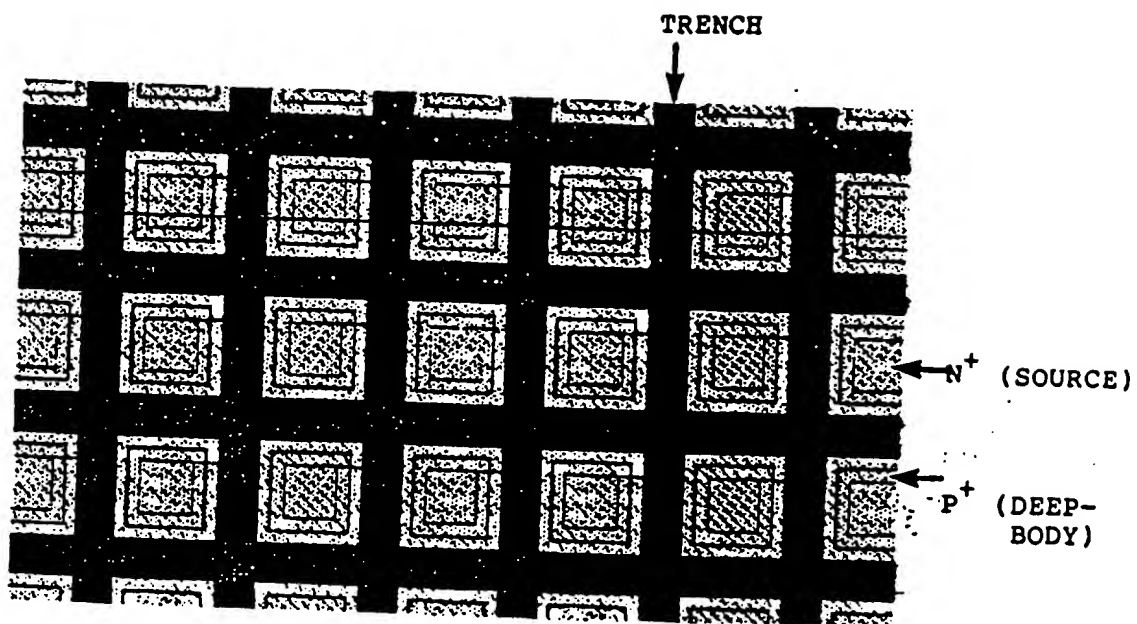


Figure 2,b

"Closed-cell" implementation of a trench DMOS  
power transistor (CALMA hard copy, active region).  
Siliconix, Inc., 1987.

read + understood J. Q. K. W. H. August 10, 1988  
read and understood Randolph D. Loh August 11, 1988

A2.4/QD5.3

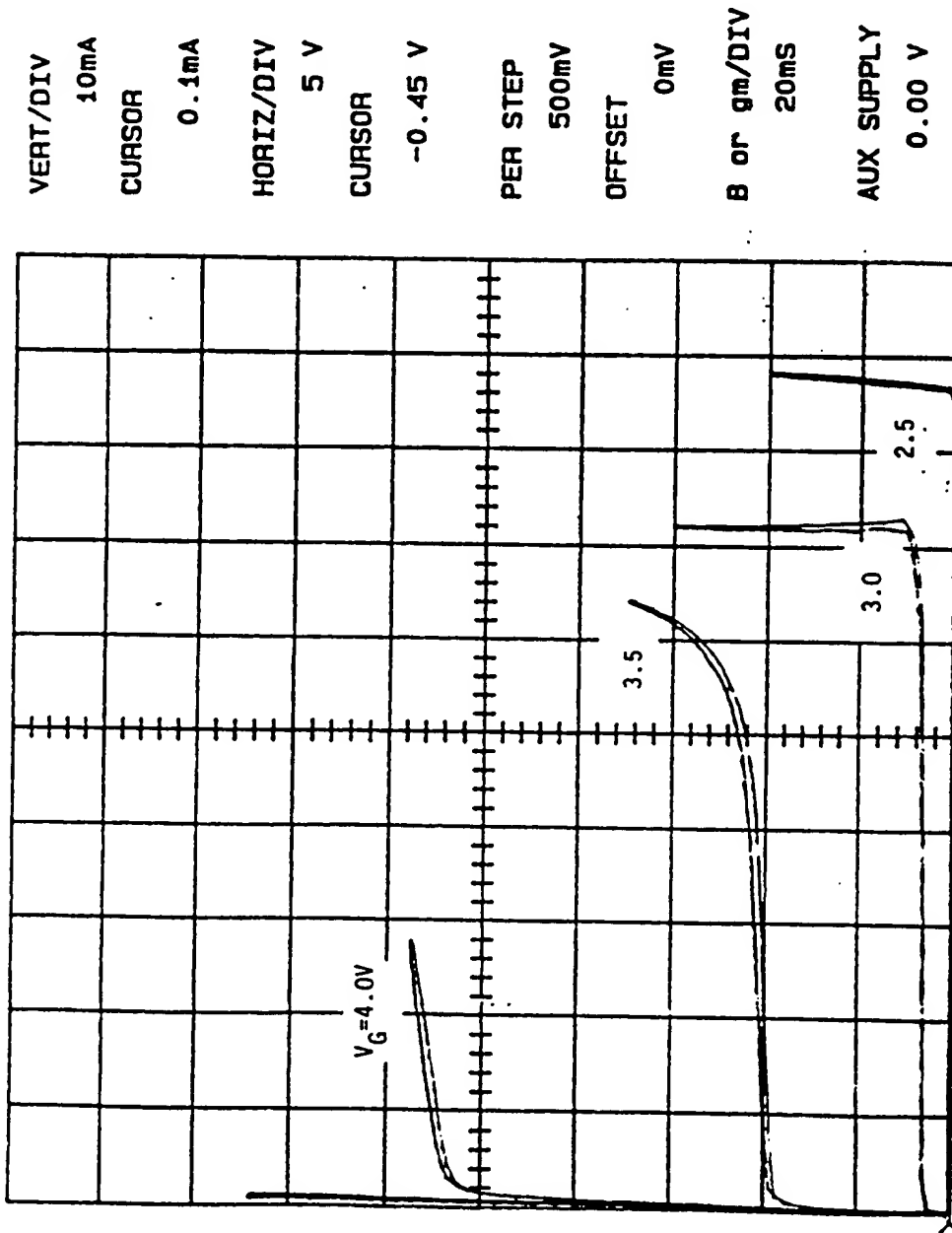


Figure 3,a

Output I-V characteristics of an experimental "open-cell" trench MOS transistor having distant body contacts, perpendicular to the trenches. Siliconix, Inc., 1988.

read & understood... August 10, 1988  
 read and understood August 11, 1988 Paul H. D. M.

A2.1/QD5.3

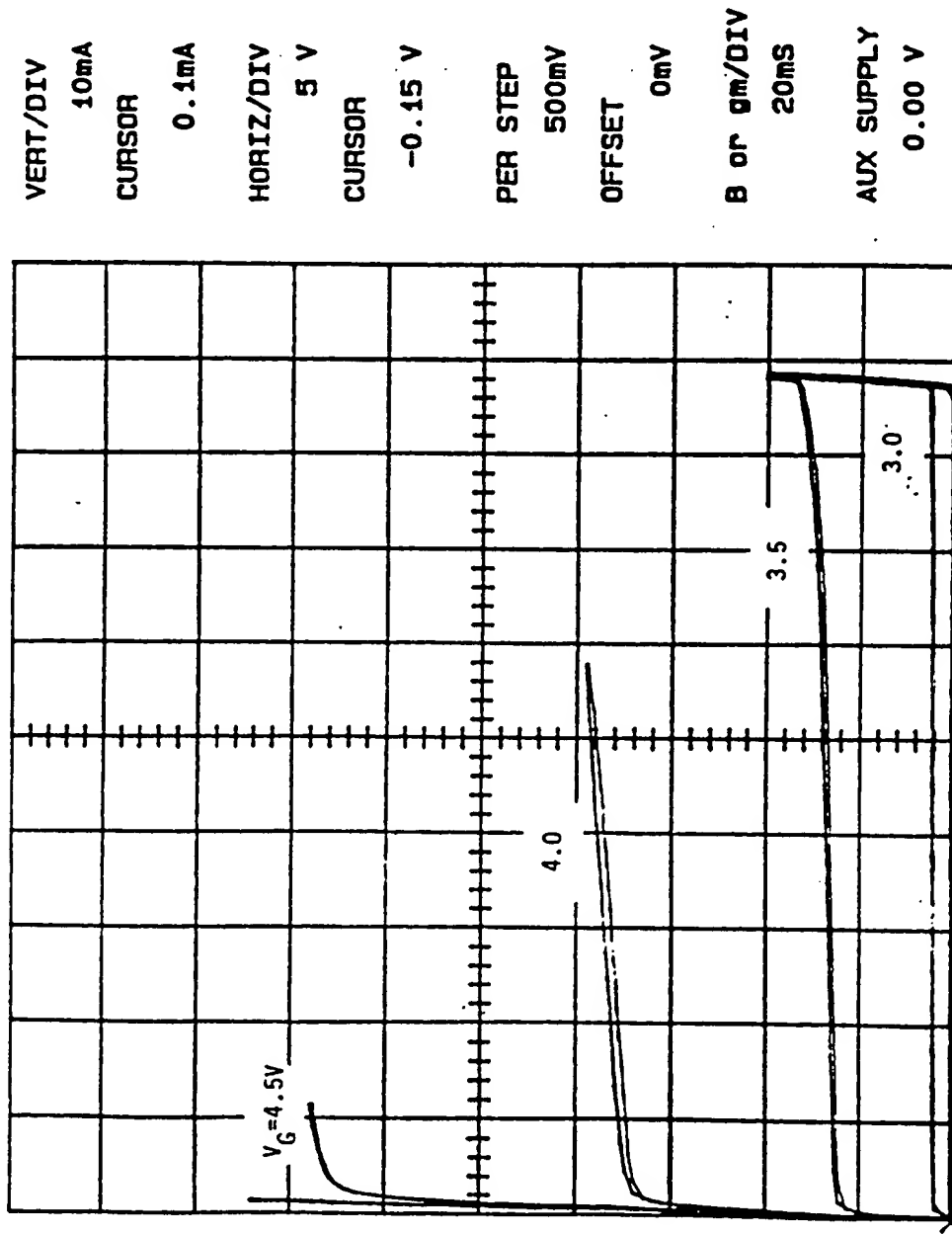


Figure 3,b

Output I-V characteristics of an experimental "open-cell" trench MOS transistor having closely-spaced body contacts, perpendicular to the trenches. Siliconix, Inc., 1988.

read & understood Q. K. W. August 10, 1988  
read and understood Randolph D. Lee August 11, 1988

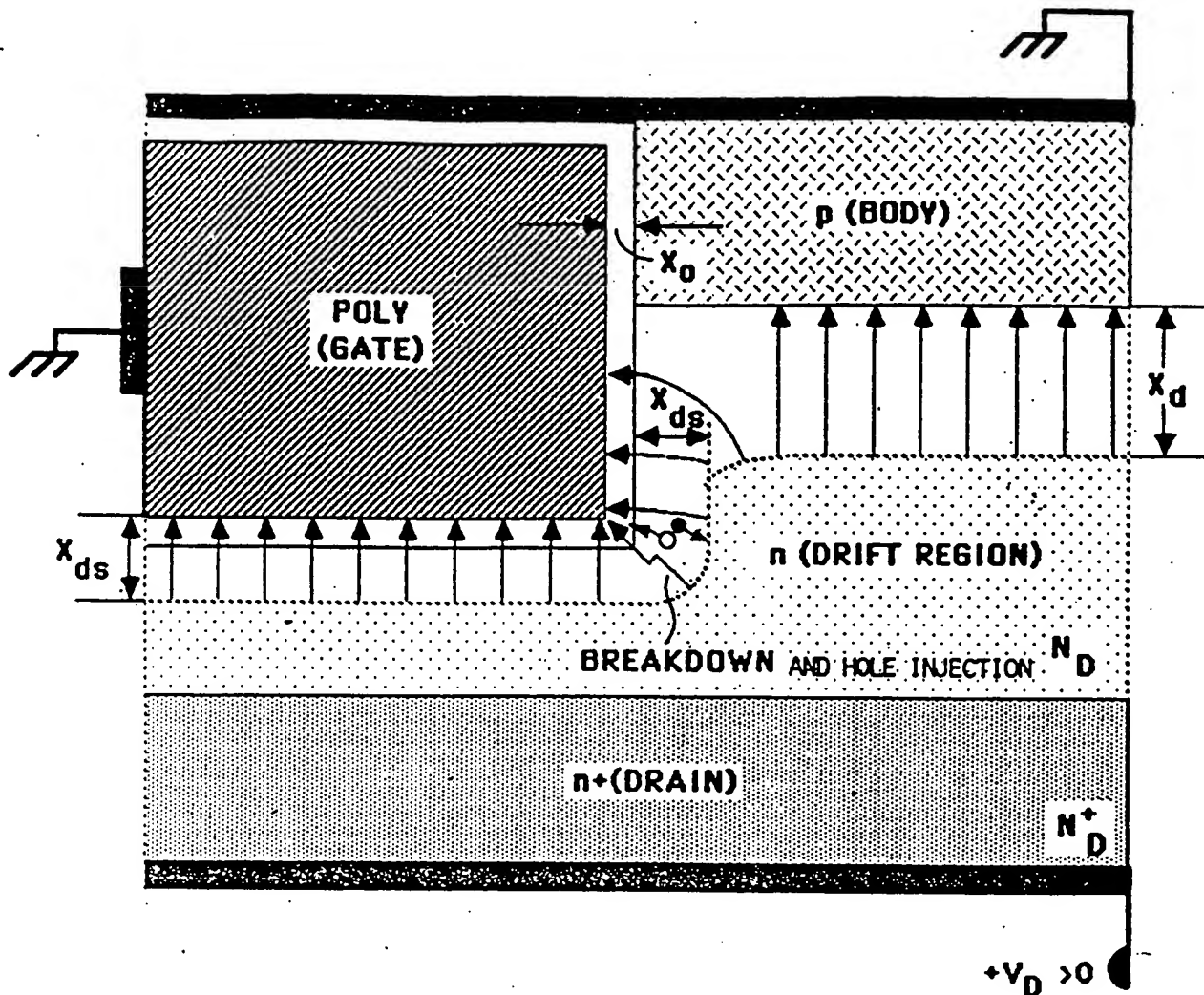


Figure 4

Qualitative description of the electric-field structure in a trench DMOS transistor having no deep-body profile provision. BVDSS biasing, source junction omitted.

read & understood Q. K. W. August 10, 1988  
read and understood Randolph D. M. August 11, 1988



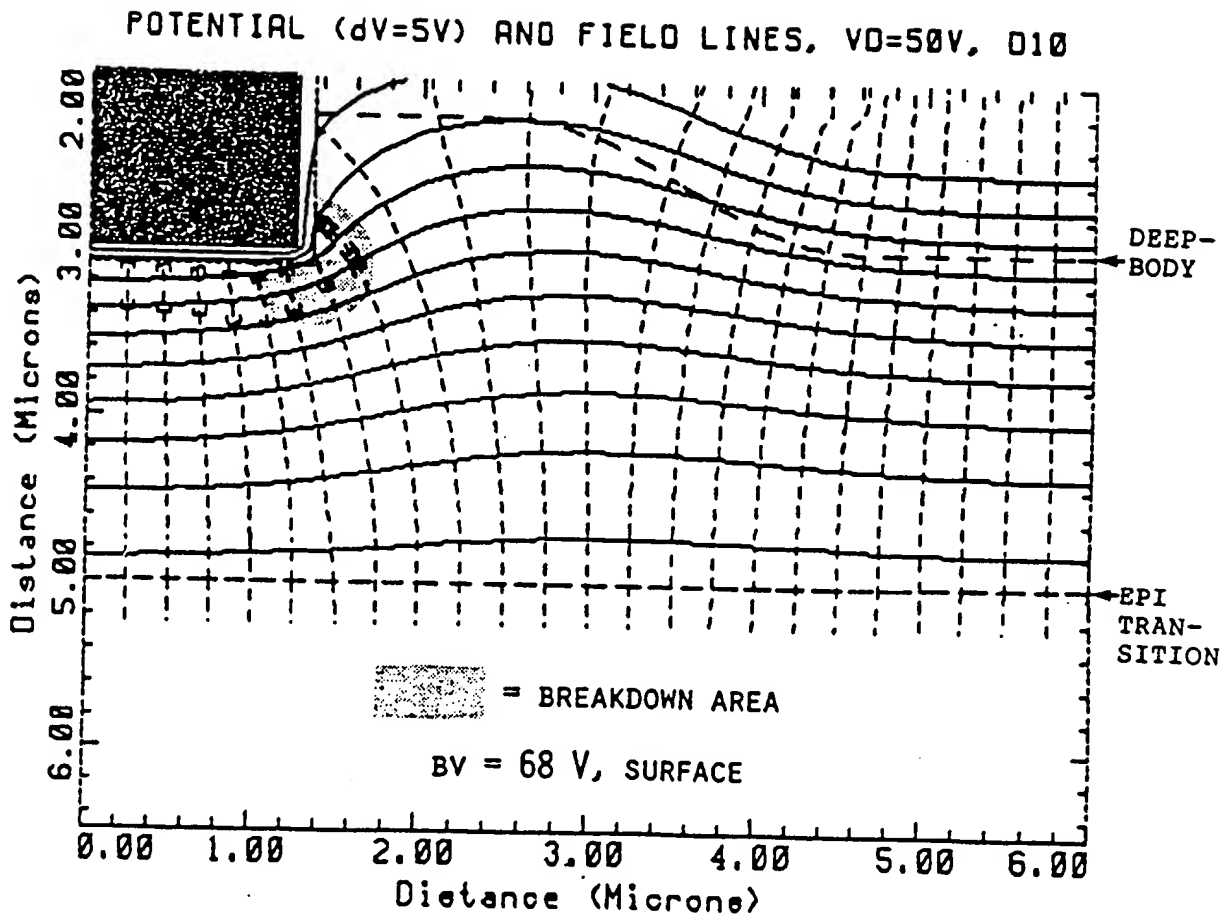


Figure 5

2-D computer simulation of the BVDSS operation of a trenched DMOS transistor having the deep body junction shallower than the trench. Drain breakdown takes place beneath the trench surface.

read & understood Q-K WJA August 10, 1988  
 read & understood Ruchoff D. WJA August 14, 1988

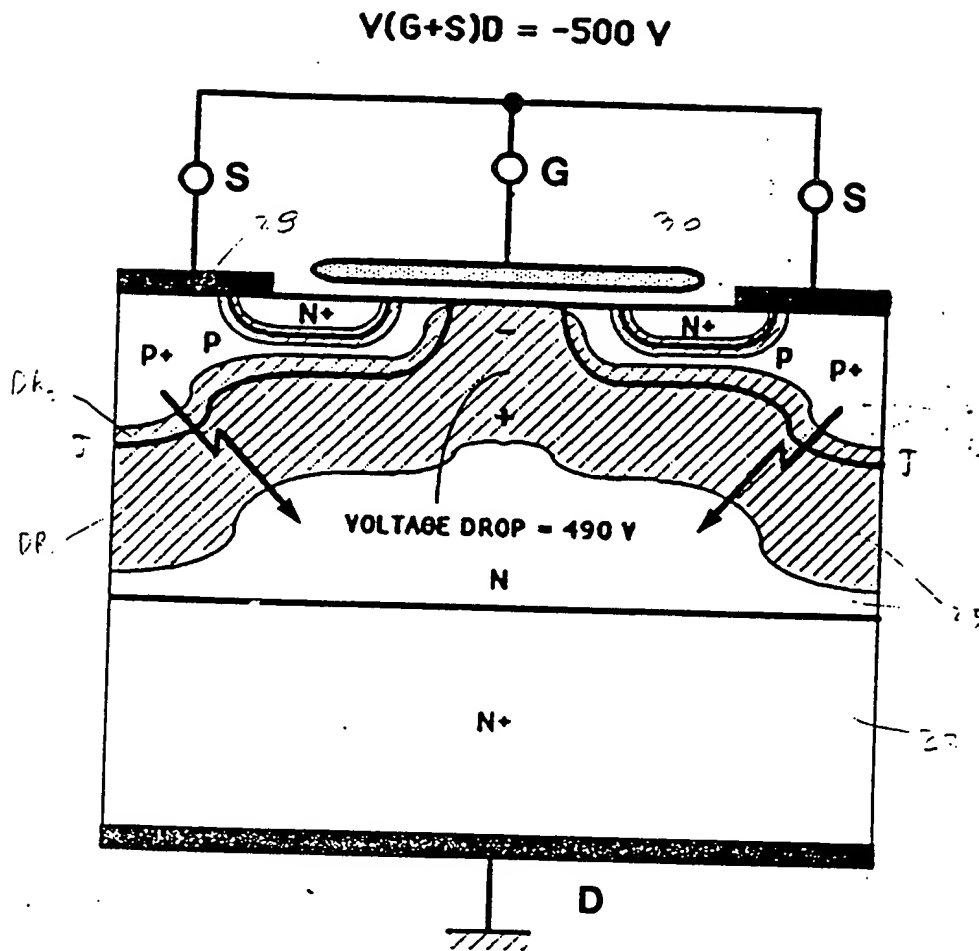


Figure 6

Junction and depletion-region topology  
of a planar DMOS transistor biased in the BVDSS condition.

rec'd + ... t... Q.K.W. Aug. 10, 1988  
rec'd at ... R. ... Aug. 14, 1988

# 2-D OXIDATION SQUARE-CELL DESIGN

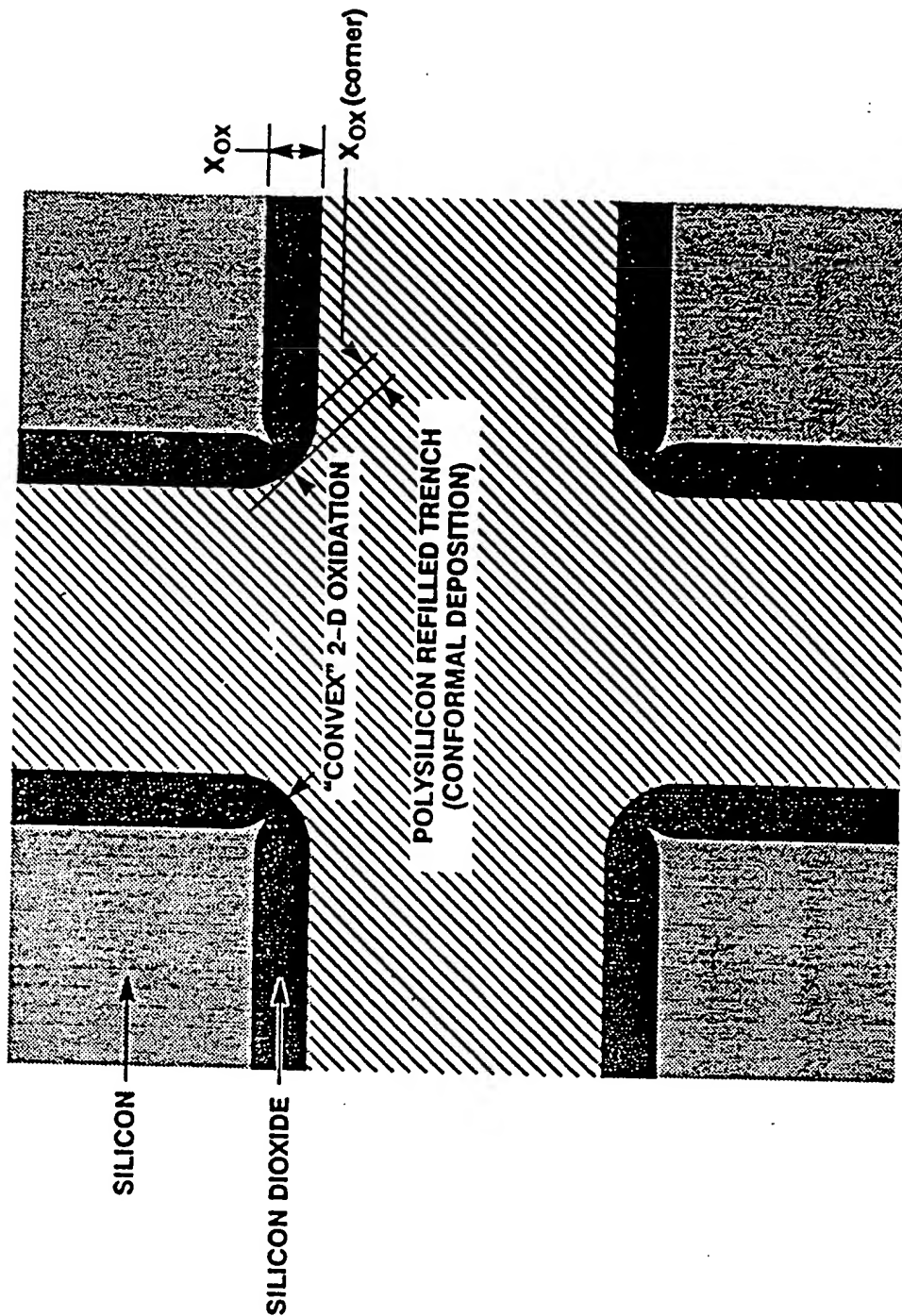


Figure 7

Qualitative description of the oxide profile  
at a rectangular trench intersection.

read & understood QKWA August 10, 1988  
read and understood Ralph Debel August 4, 1988

# HEXAGONAL-CELL TDMOS

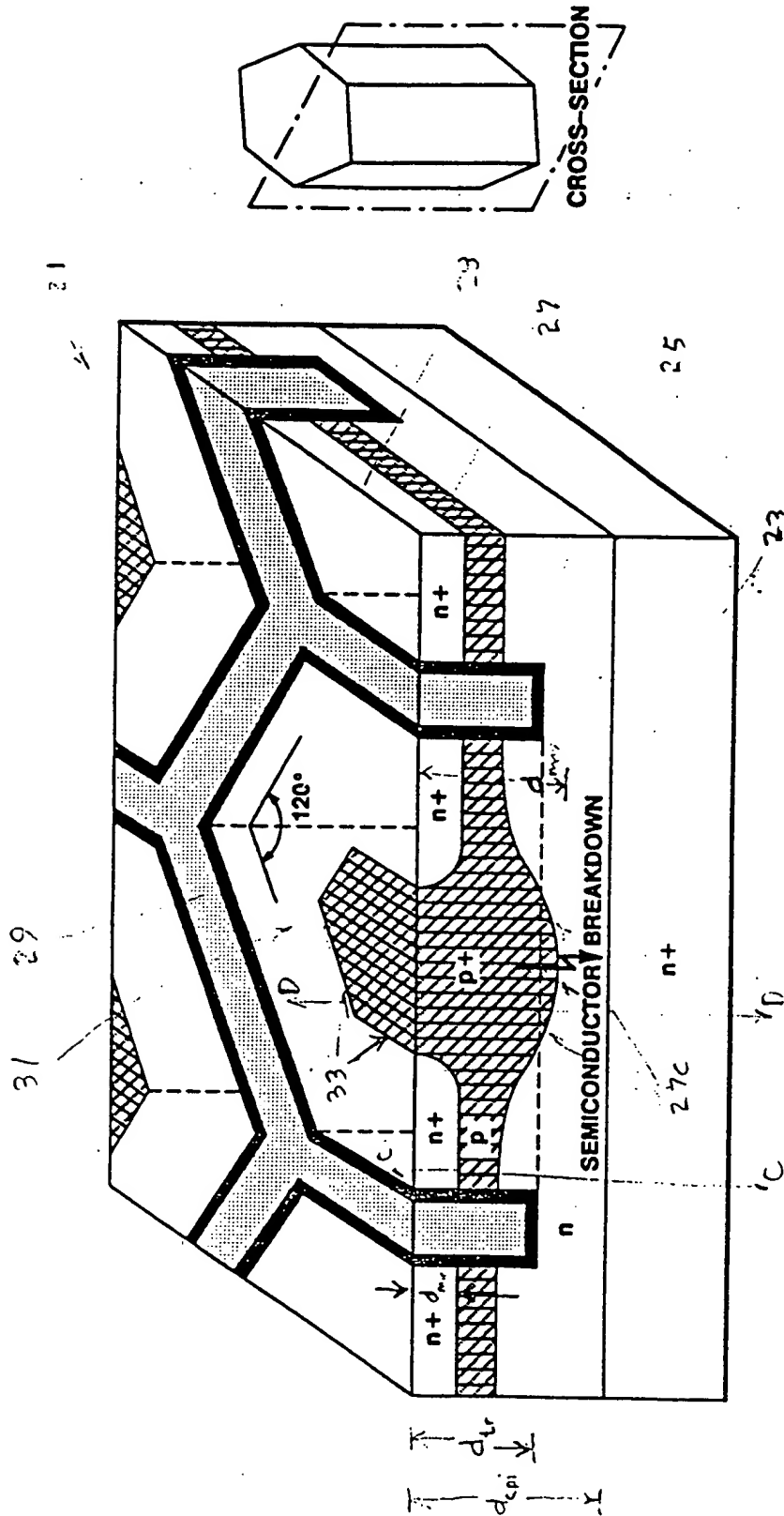
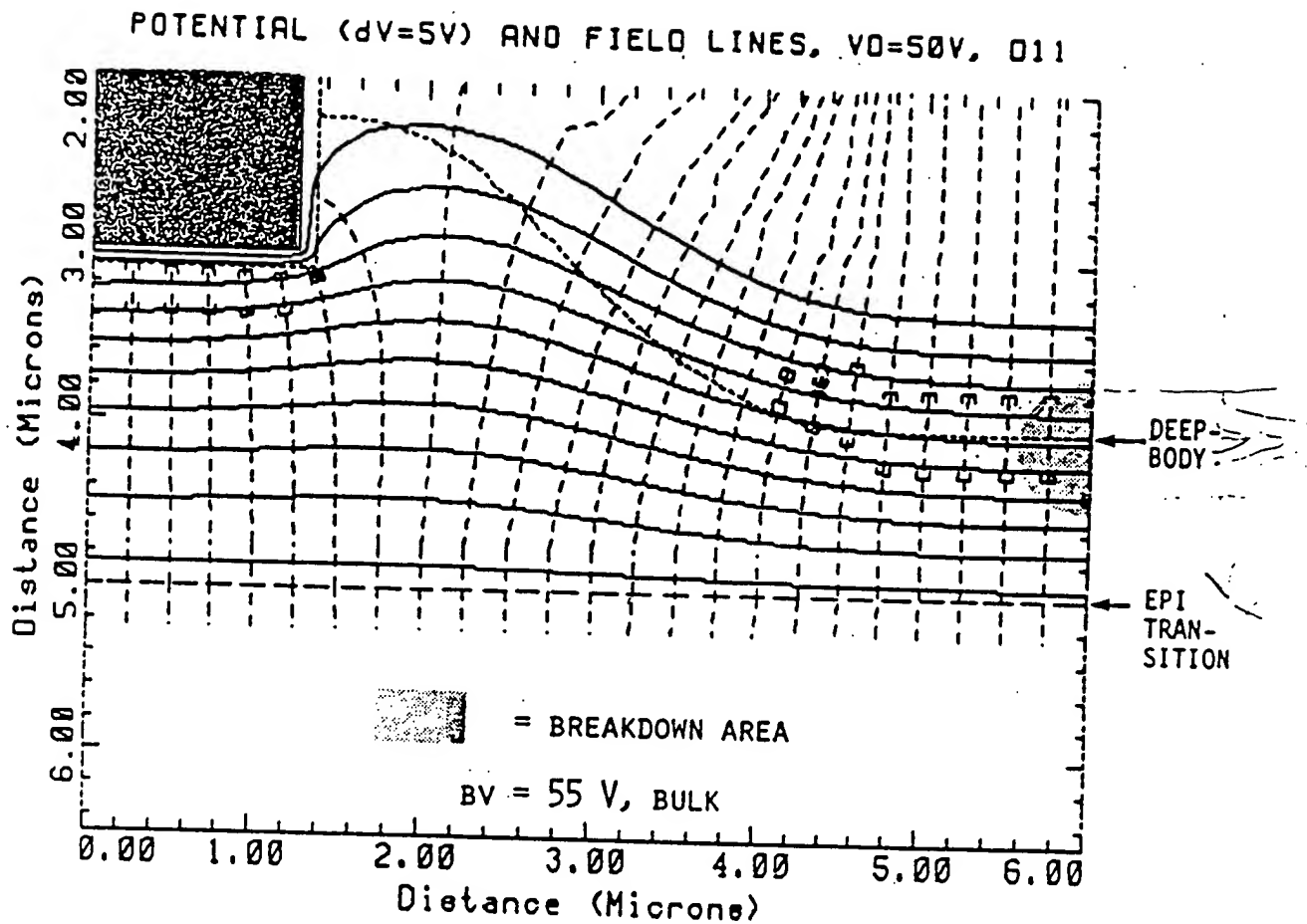


Figure 8

3-D representation of the optimized trench MOS transistor cell proposed in this Patent Application.

read & understood by KWA August 10, 1988  
read & understood by R. D. L. August 11, 1988



$$\alpha_{eff} \approx 1, \quad \alpha_{eff} = \text{strong (exp) funct. of } E$$

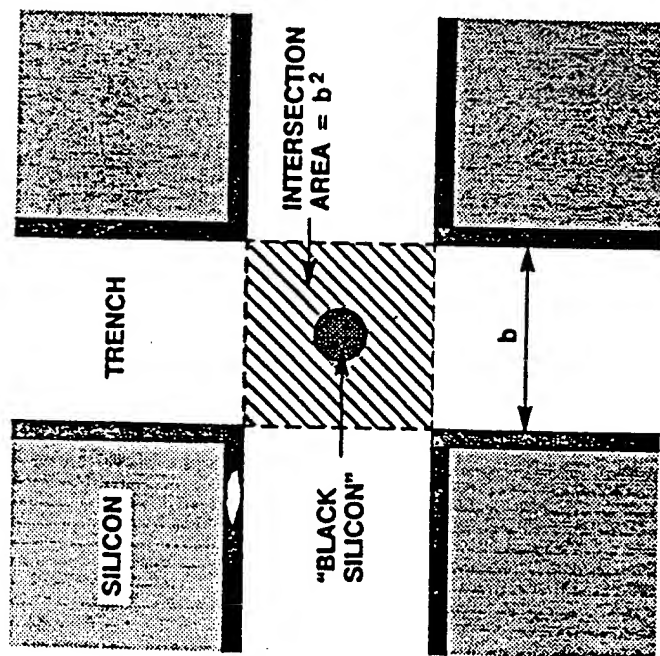
$$\alpha_{eff} = A E C^{-B/E}$$

Figure 9

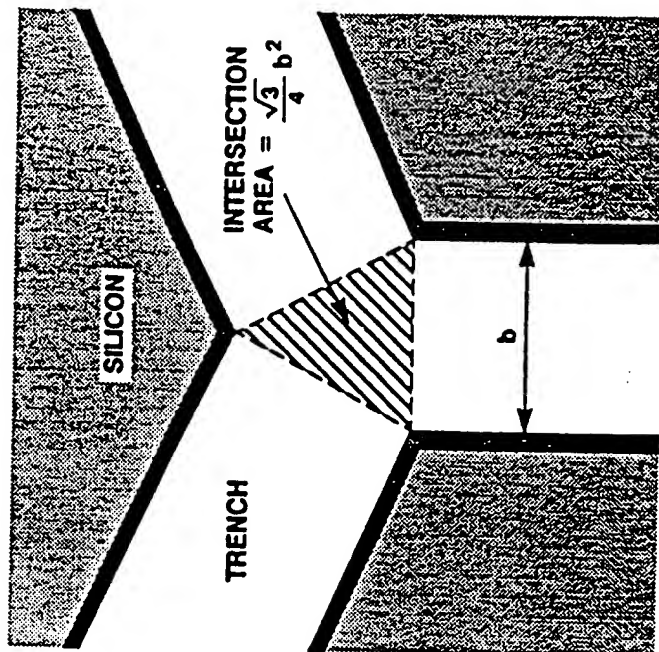
2-D computer simulation of the BVDSS operation of a trench MOS transistor having the deep body junction deeper than the trench. Drain breakdown takes place in the bulk.

received... to... *[Signature]* August 10, 1988  
 read and understood *[Signature]* August 4, 1988

# "BLACK SILICON" COMPARISON



SQUARE CELLS



HEXAGONAL CELLS

Figure 10

Comparison of the "black silicon" areas at trench intersections: square cell (left) versus hexagonal cell (right).

read & understood QXW August 10, 1988  
read and understood Randolph D. August 11, 1988

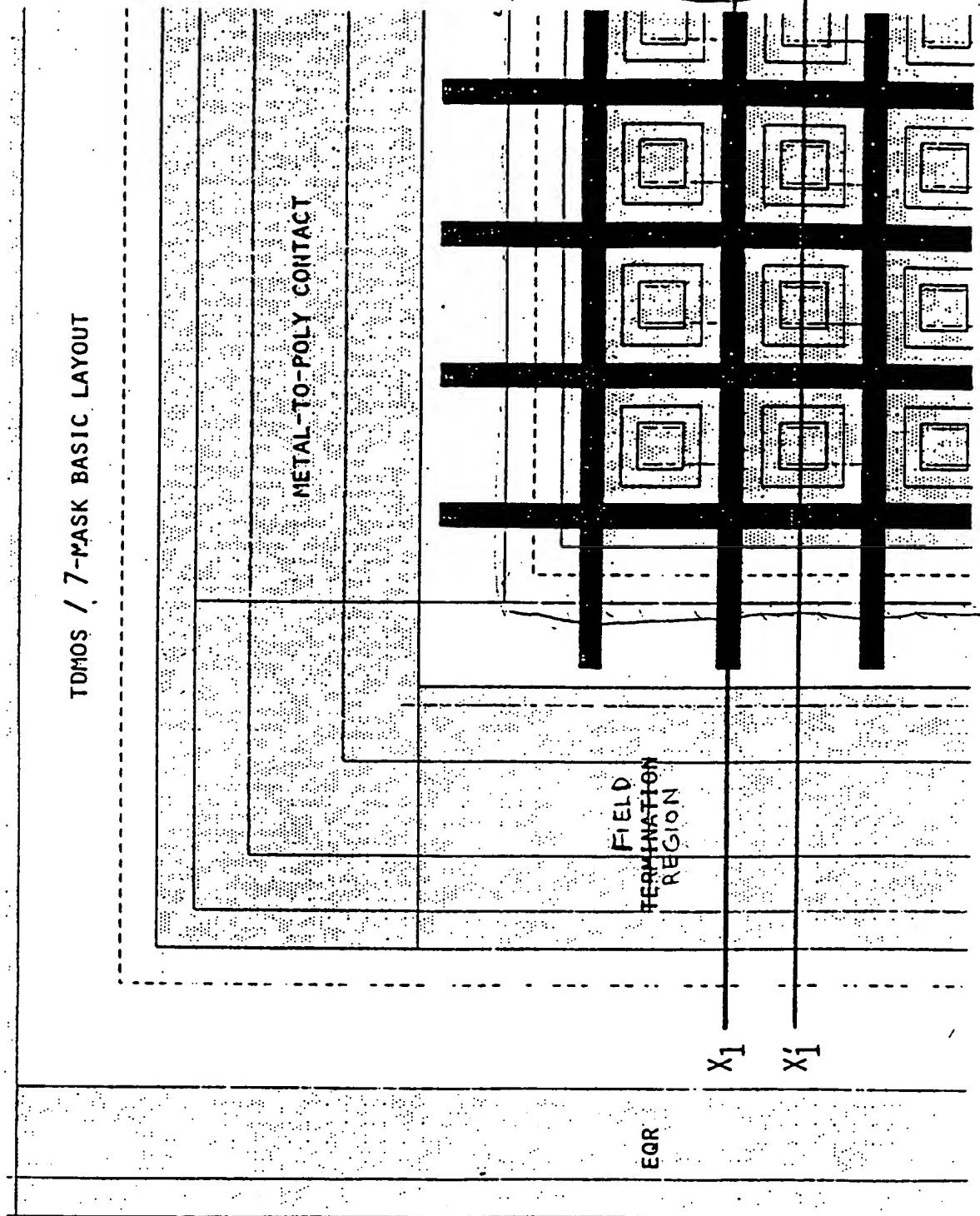


Fig. 21

read and understood QK WLL August 10, 1988  
 read and understood Randolph D. WLL August 11, 1988

7-MASK TDMOS - PROCESSING BLOCK 1

n/n+ EPI → POST-EPI OXIDATION → MASK 1 = DEEP BODY → BORON IMPLANT & DIFFUSION / OXIDATION →

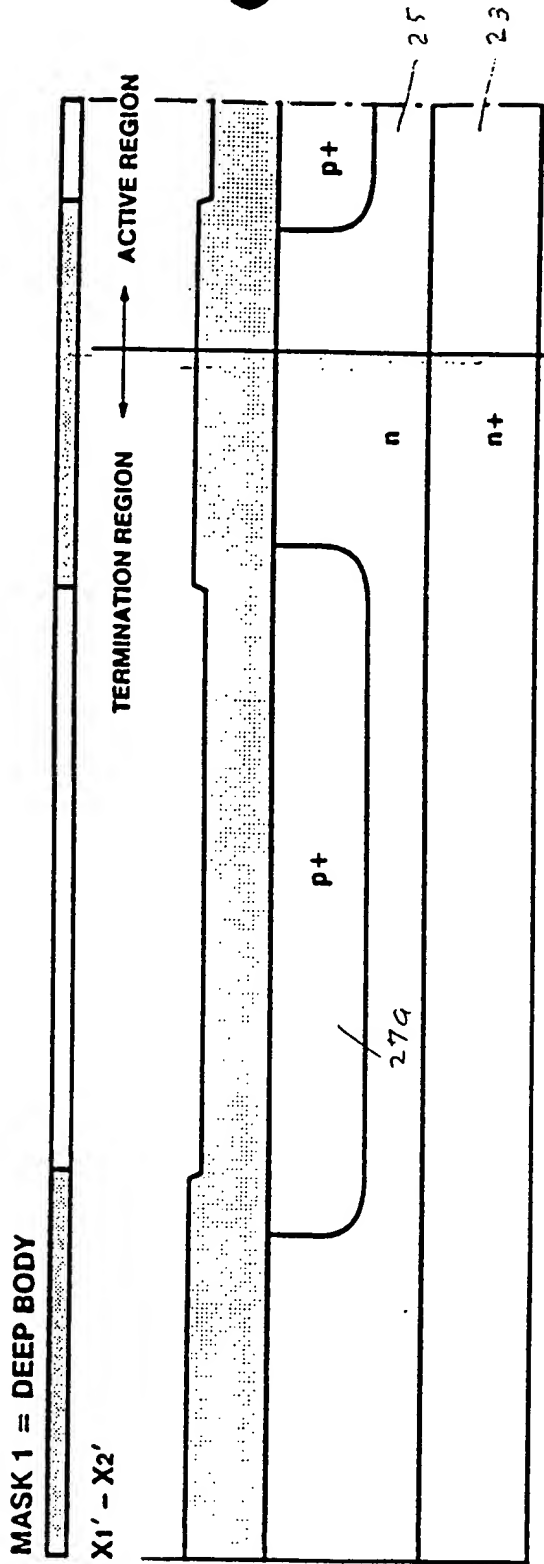


Fig. 22A

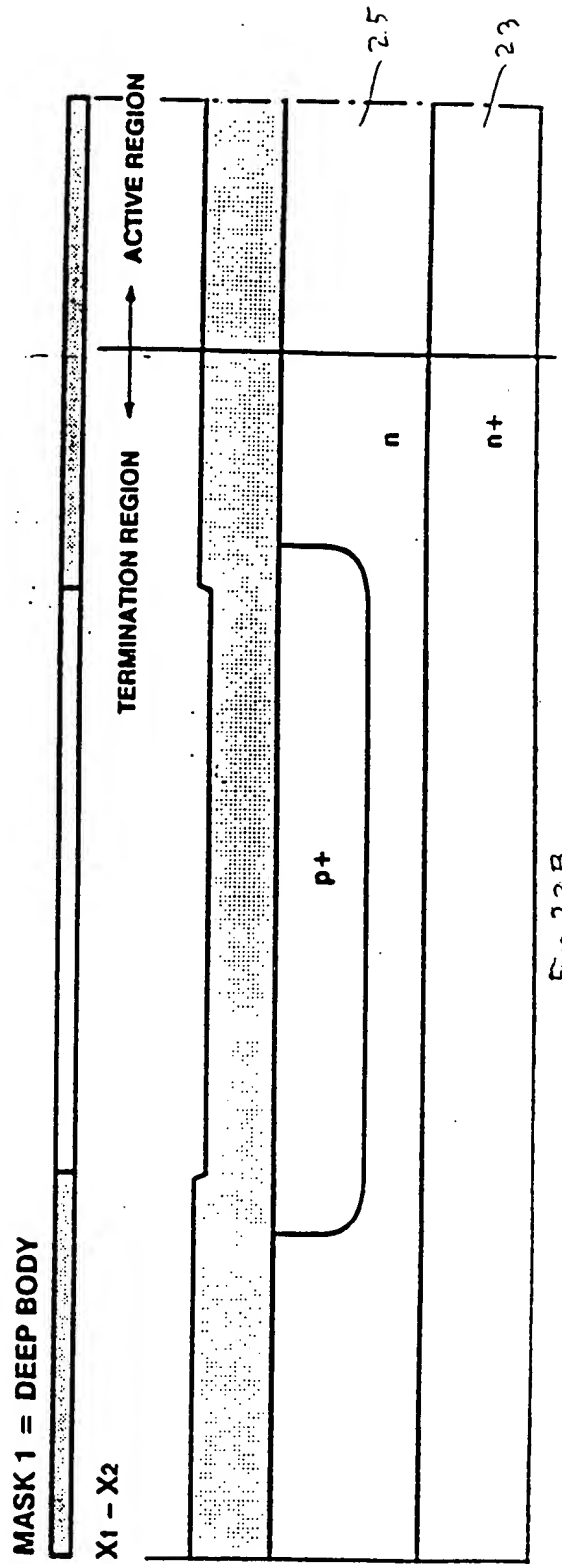


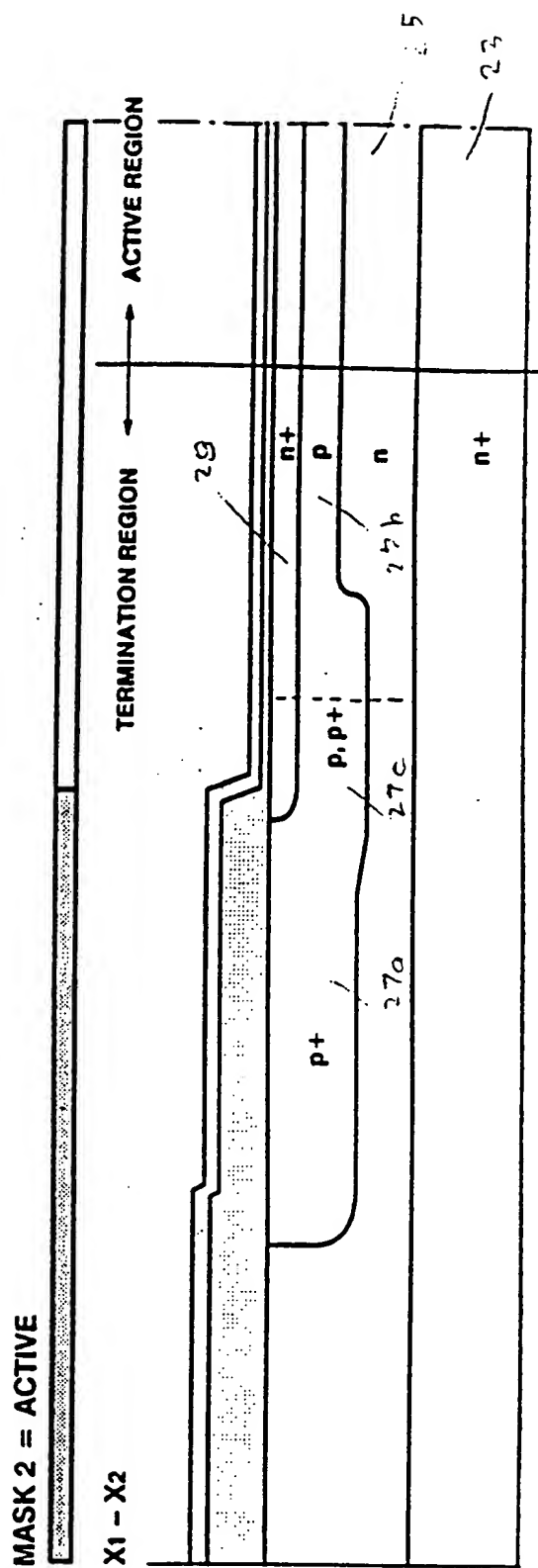
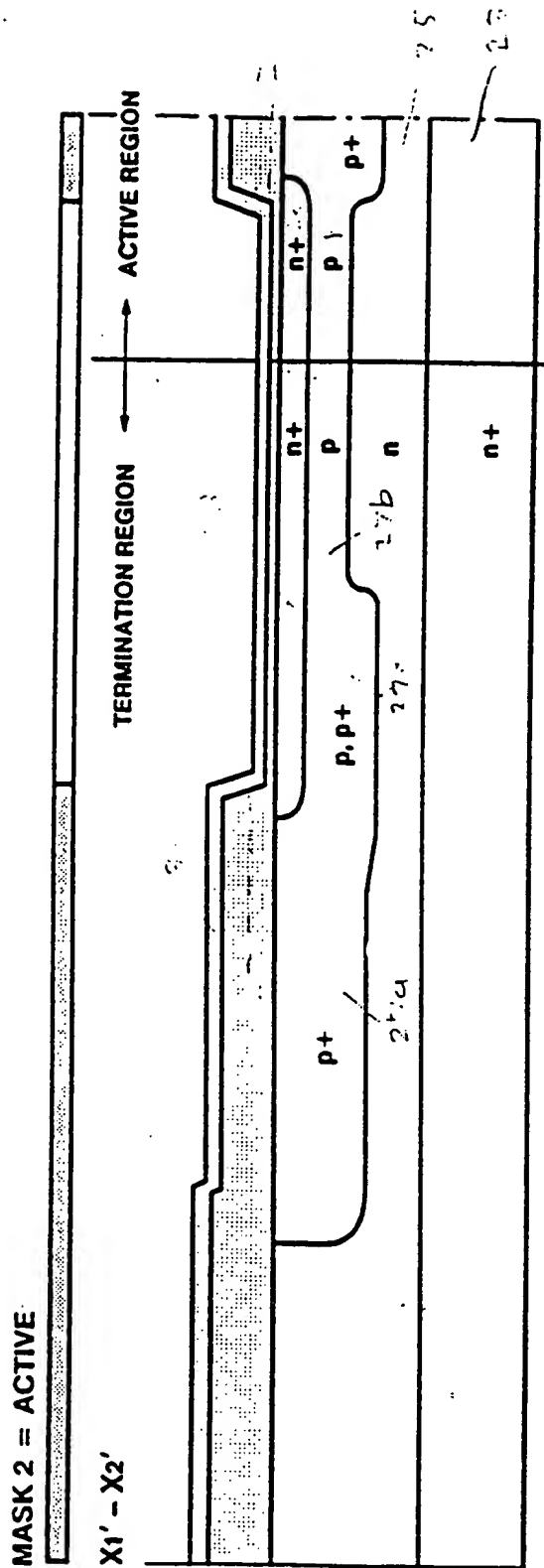
Fig. 22B

read and understood G2KWA August 10, 1988  
read and understood Randolph D. Loh August 4, 1988



# 7-MASK TDMOS — PROCESSING BLOCK 2

→ MASK 2 = ACTIVE → BORON IMPLANT & DIFFUSION / OXIDATION → ARSENIC IMPLANT & DIFFUSION / OXIDATION → LTO DEPOSITION



read & understood Q.K.W.H. August 10, 1988  
read and understood Paul High Dole August 11, 1988

7-MASK TDMOS - PROCESSING BLOCK 3

 MASK 6 = TRENCH 
  TRENCH DRY ETCHING 
 

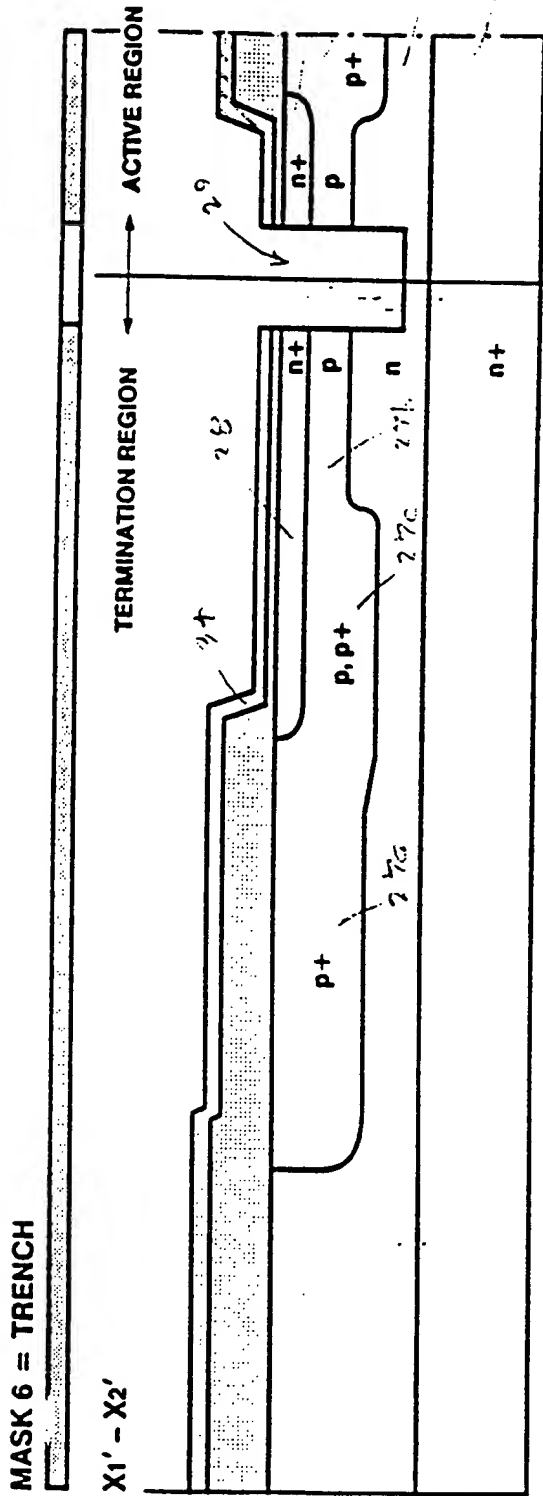


Fig. 24-A

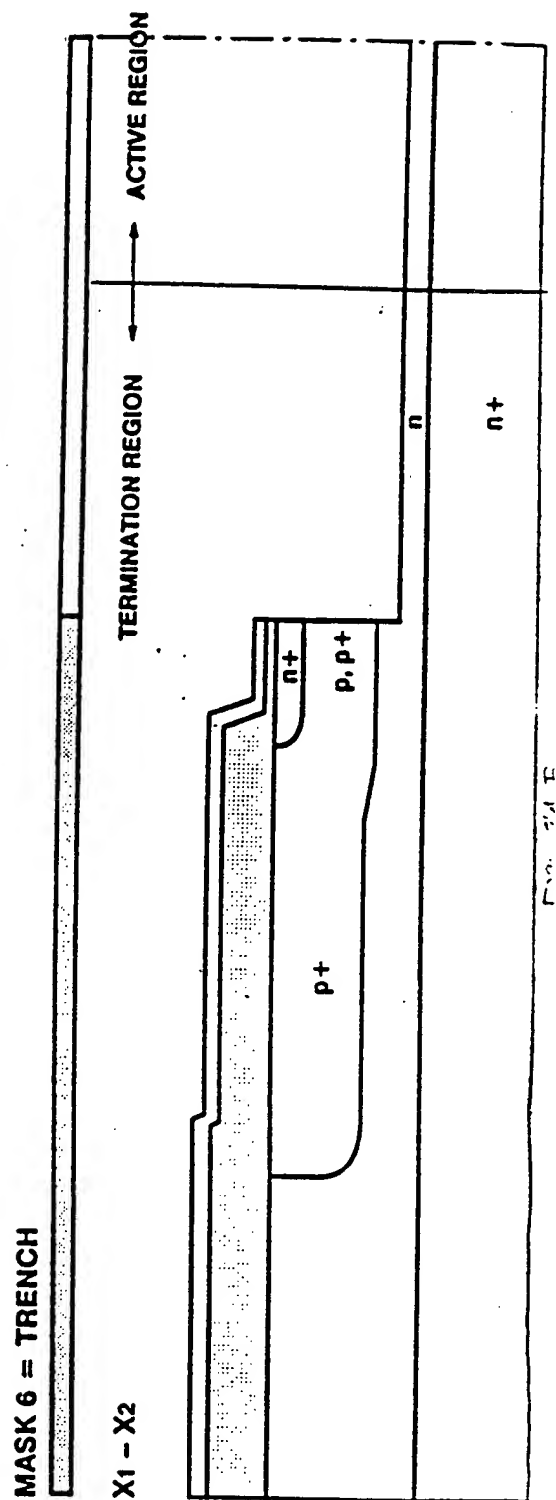
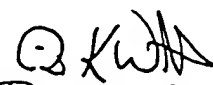
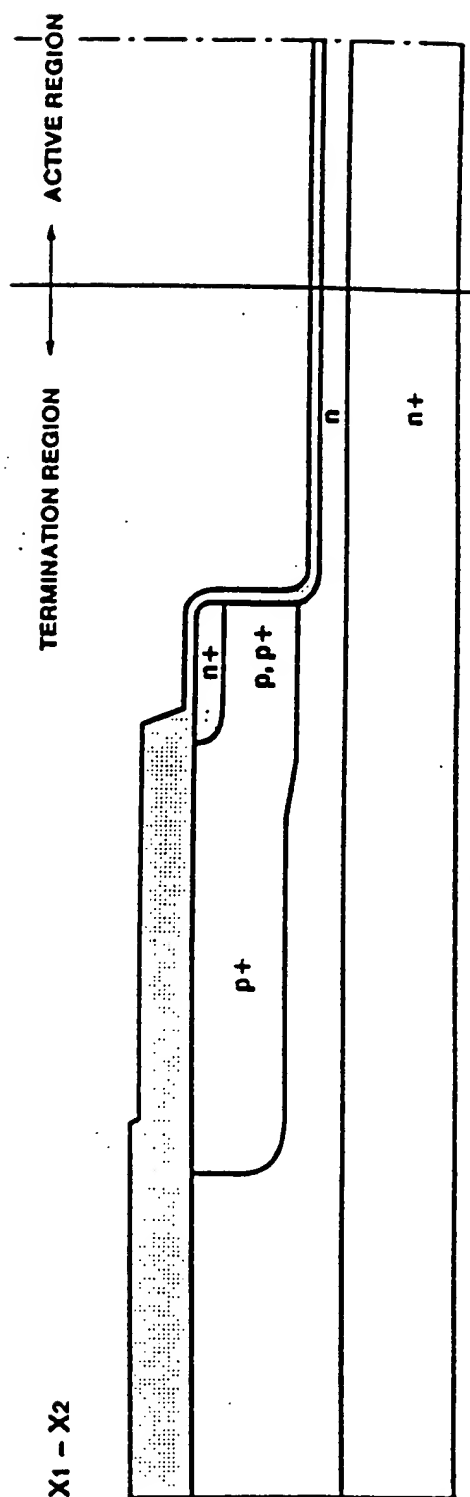
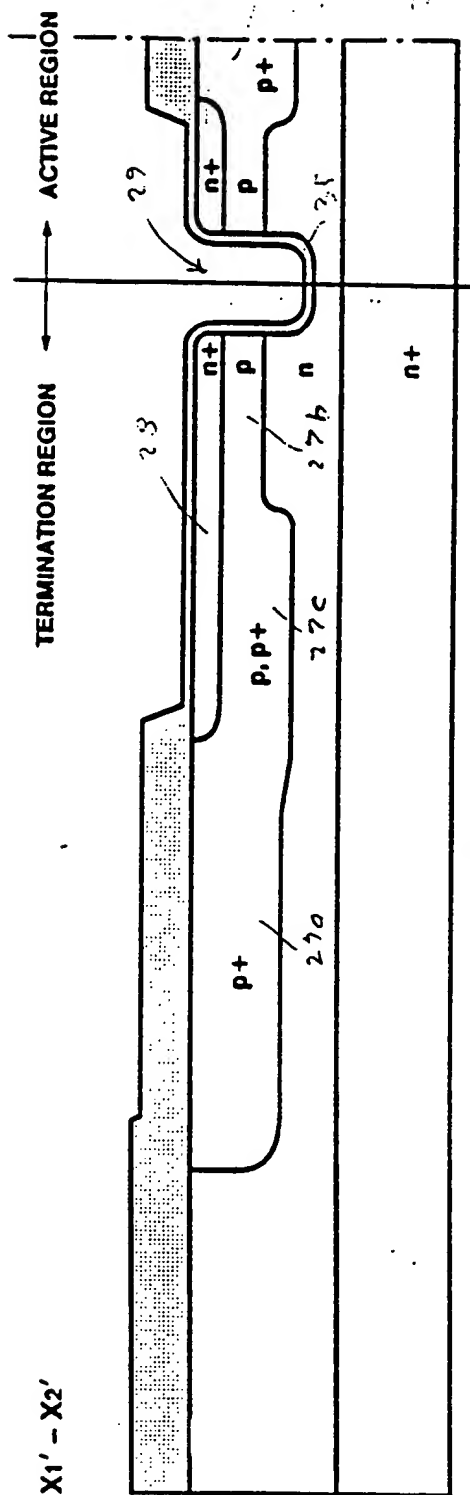


Fig. 24-B

read + understood  August 10, 1988  
 read and understood Randolph D. Clark August 11, 1988

# 7-MASK TDMOS — PROCESSING BLOCK 4

➡ SACRIFICIAL OXIDATION & ETCHING ➡ GATE OXIDATION ➡



read & understood QXW August 10, 1988  
read and understood Ralston August 11, 1988

# 7-MASK TDMOS -- PROCESSING BLOCK 5

→ FIRST POLY DEPOSITION & PHOSPHORUS DOPING → OXIDATION (ETCH STOP) →

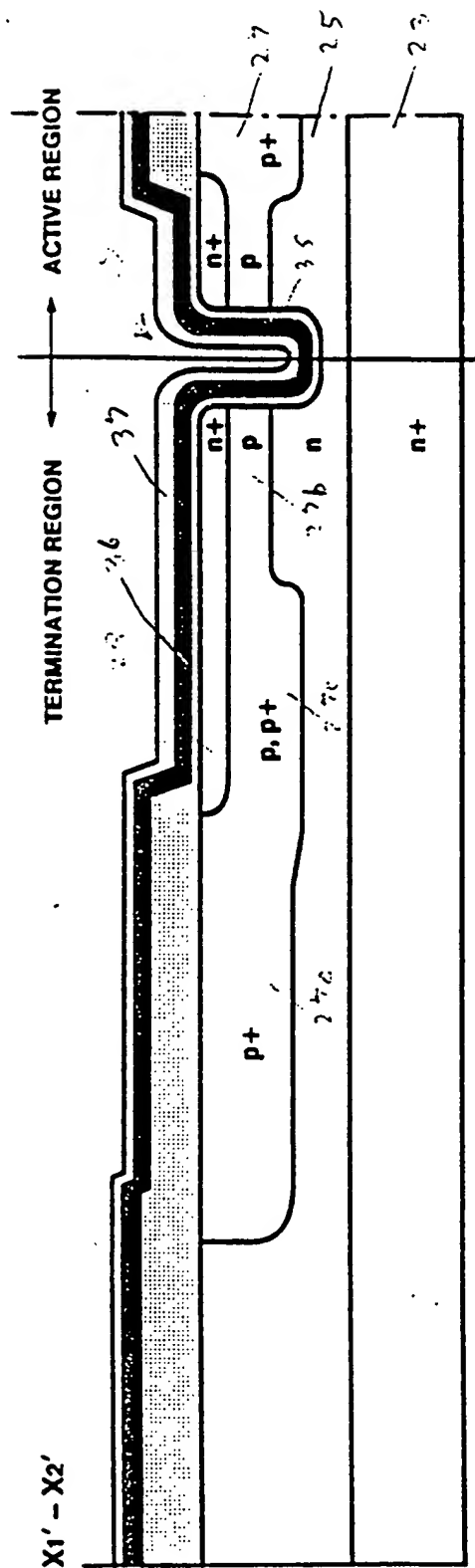


Fig. 26A

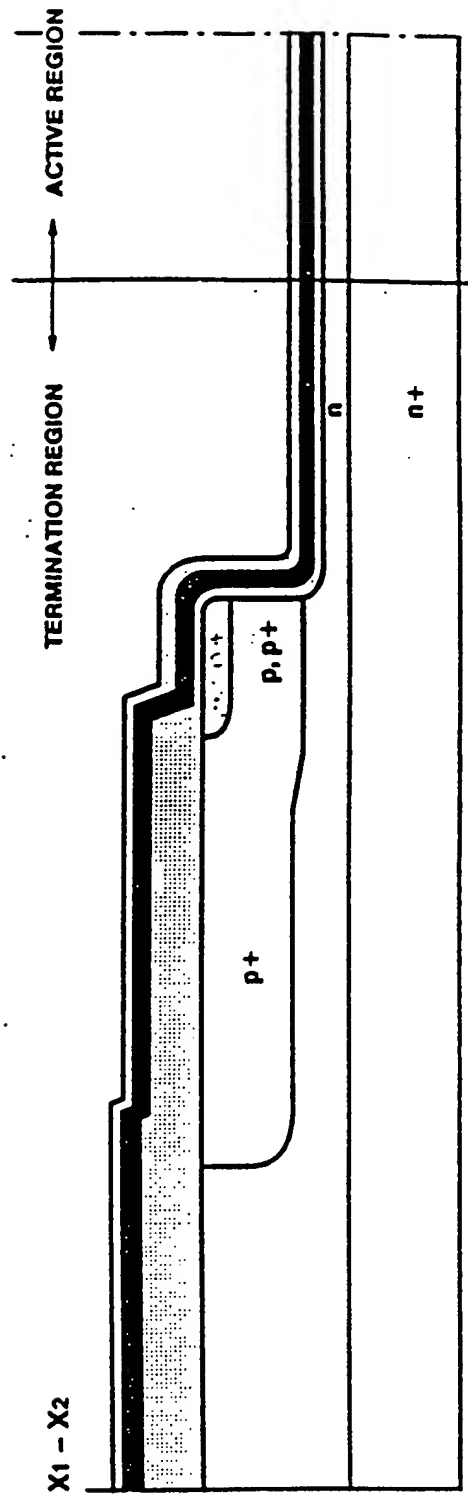


Fig. 26B

read & understood *[Signature]* August 10, 1988  
read and understood *[Signature]* August 11, 1988

7-MASK TDMOS - PROCESSING BLOCK 6

→ SECOND (UNDOPED) POLY DEPOSITION →

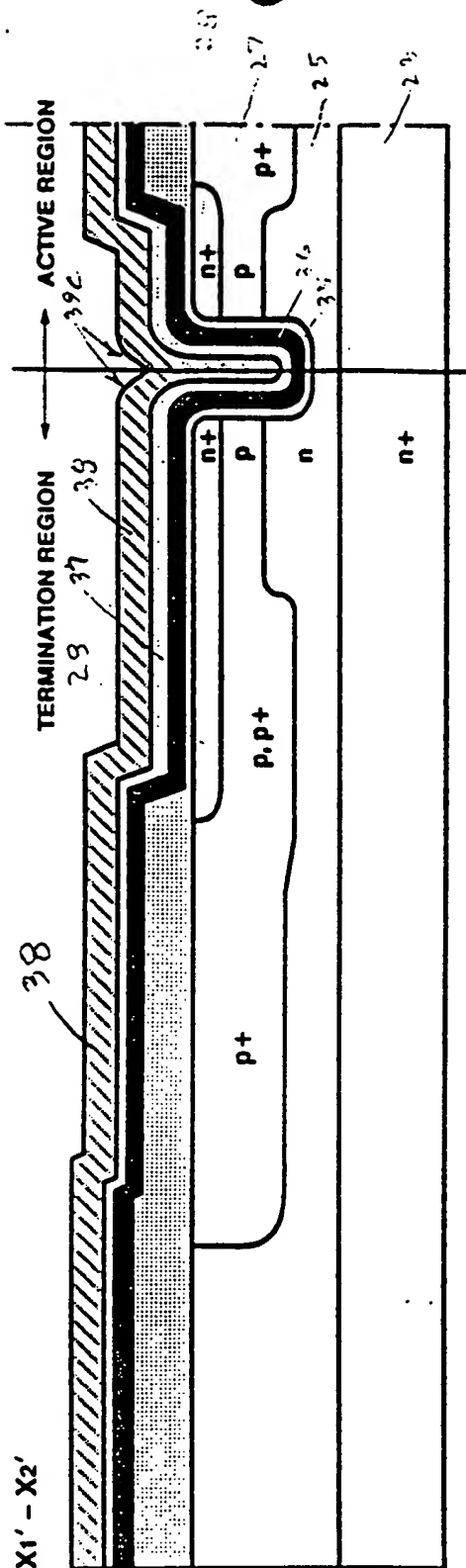


Fig. 27A

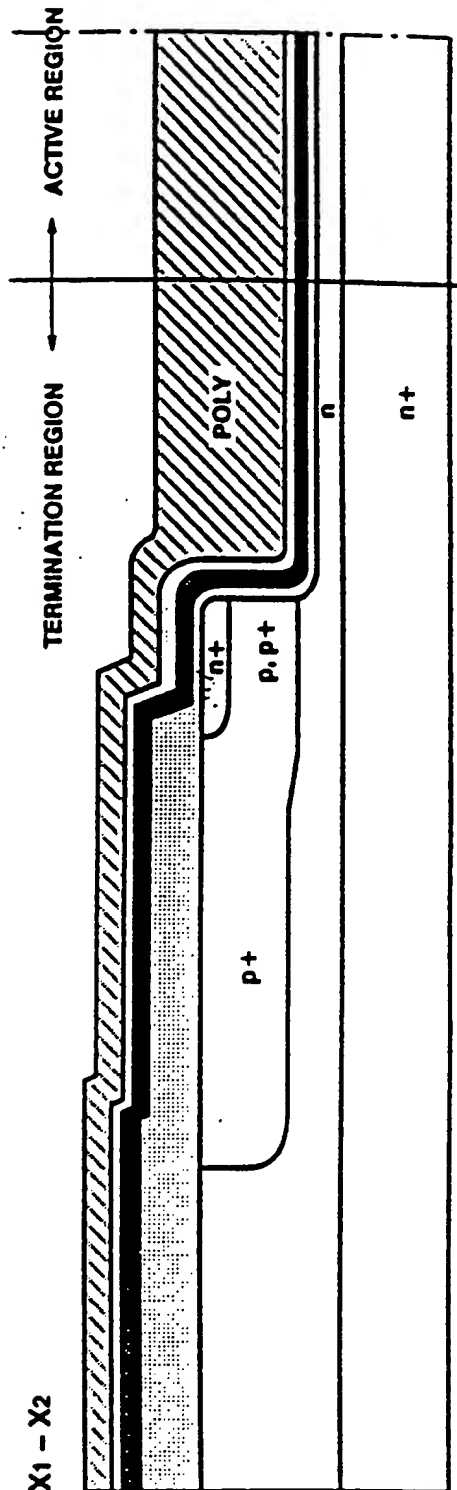
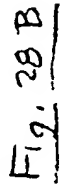
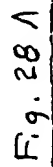


Fig. 27B

read & understood QKWH August 10, 1988  
read and understood Randolph D. Leh August 11, 1988

 POLY PLANARIZATION ETCHING
  ETCH-STOP-OXIDE STRIP
 



read & understood *OKW* August 10, 1988  
read and understood *Paula Dilled* August 11, 1988

7-MASK TDMOS-PROCESSING BLOCK 8

→ MASK 7 = POLY →

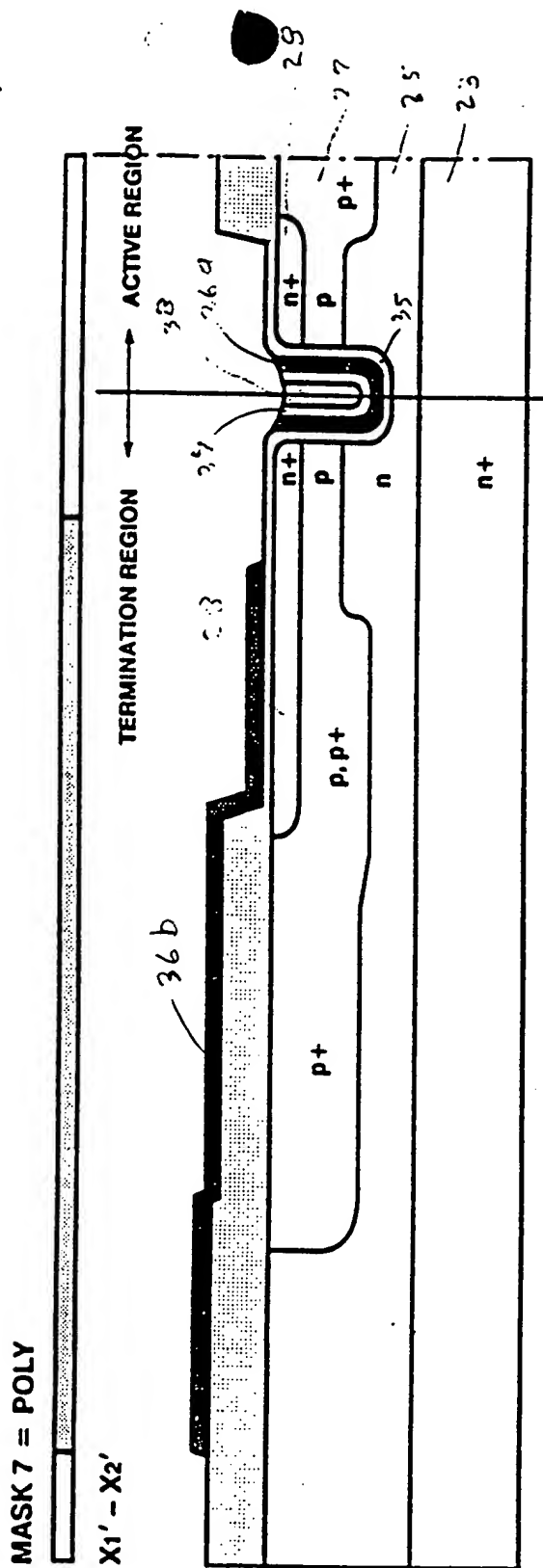


Fig. 29A

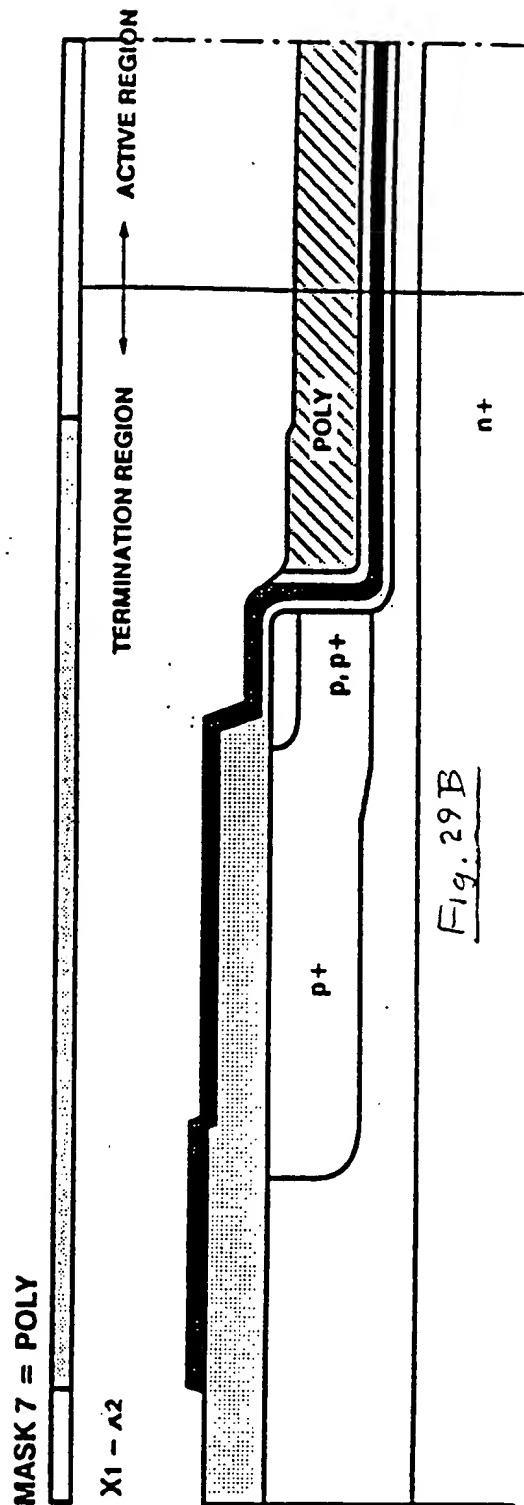


Fig. 29B

rec'd & understood Q&A August 10, 1988  
read and understood Randolph & Kel August 11, 1988

7-MASK TDMOS - PROCESSING BLOCK 9

→ OXIDATION → BPSG DEPOSITION & FLOW → MASK 8 = CONTACT → BPSG REFLOW →

MASK 8 = CONTACT

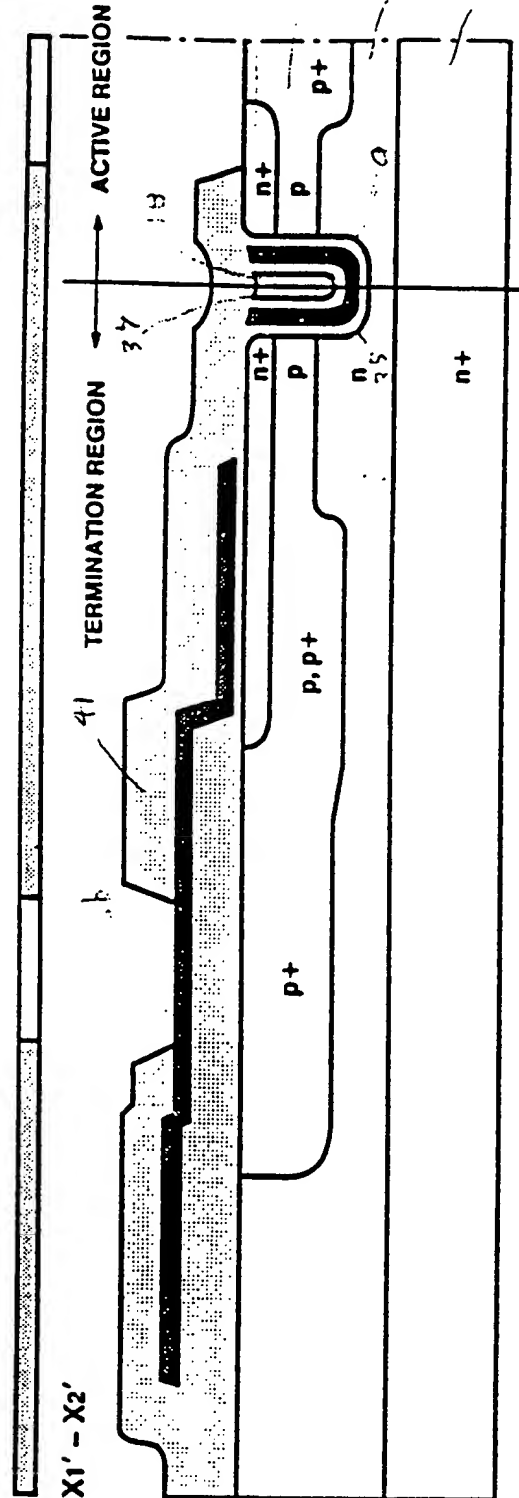
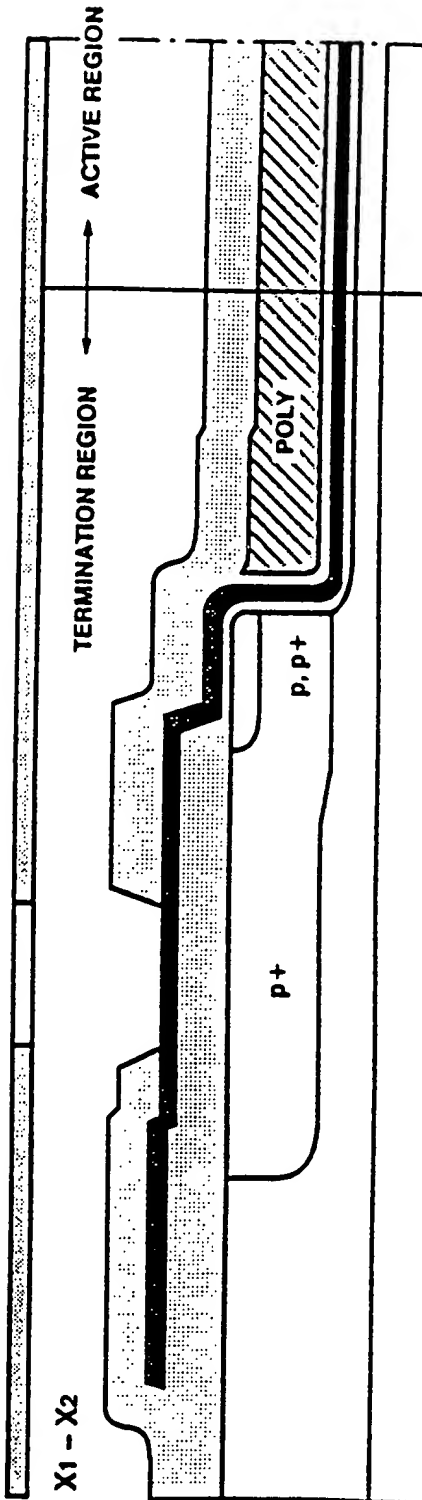


Fig. 30A

MASK 8 = CONTACT



read & understood Q&W August 10, 1988  
read and understood Randolph D. del August 11, 1988



# 7-MASK TDMOS - PROCESSING BLOCK 10

ALUMINUM DEPOSITION → MASK 8 = METAL → METAL ALLOYING → ELECTRICAL CHECK →

MASK 9 = METAL

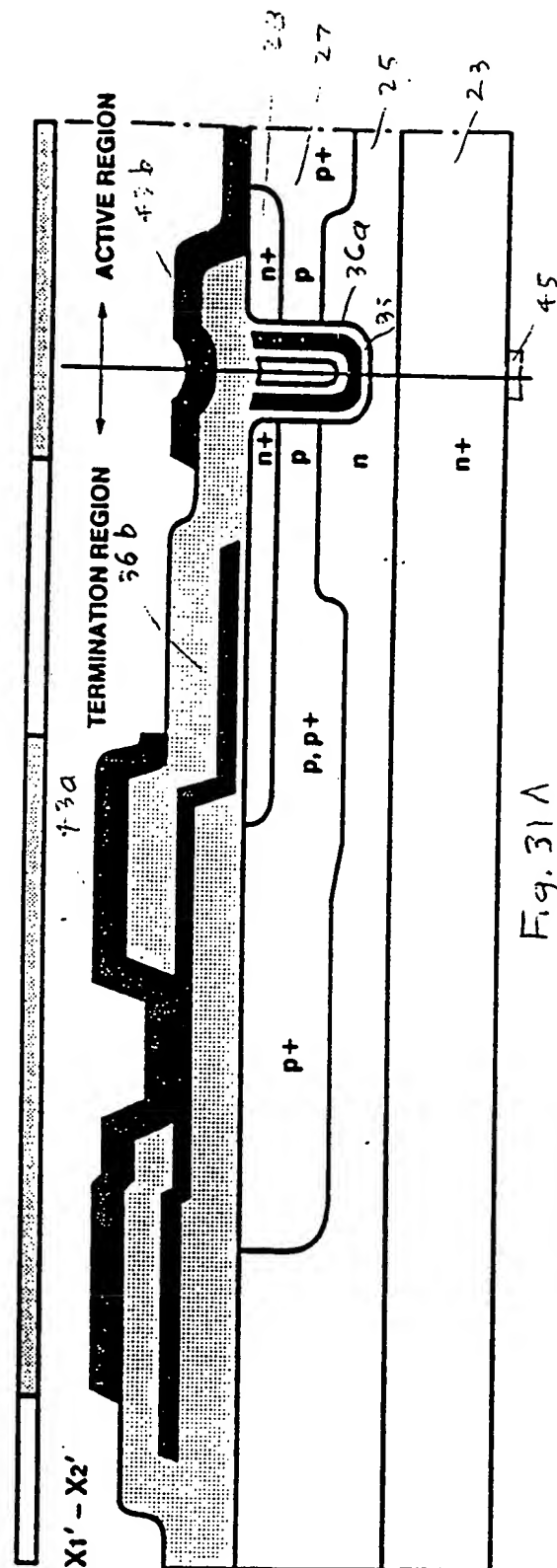
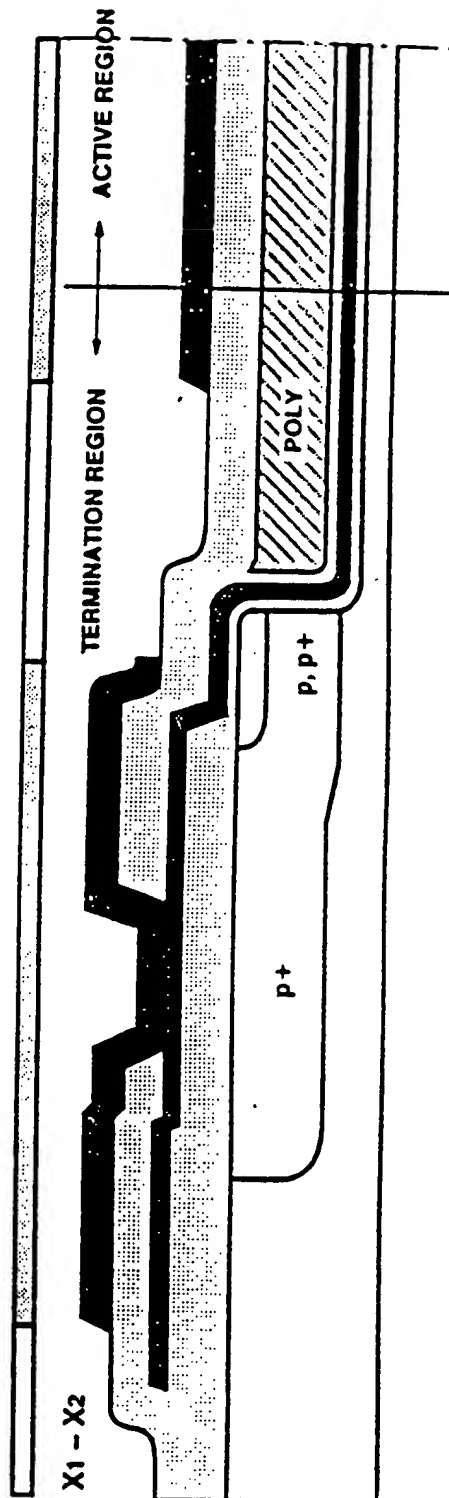
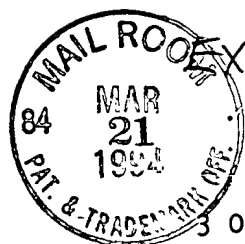


Fig. 31A

MASK 9 = METAL



read & understood Q&A with August 10, 1988  
 read and understood Randolph Debel August 11, 1988



3 October 1988

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SKJERVEN, MORRILL, MacPHERSON  
FRIEL

*Handwritten initials*

11-799



**Siliconix**  
incorporated

2201 Laurelwood Road  
Santa Clara, CA 95054  
(408) 988-8000  
TWX: 910-338-0227

Mr. Paul J. Winters  
Skjerven, Morrill, MacPherson, Franklin & Friel  
3600 Pruneridge, Suite 100  
Santa Clara, California 95051

Reference: Disclosure of Invention for TRENCHED DMOS POWER TRANSISTORS WITH  
OPTIMIZED DEEP-BODY PROFILE AND THREE-DIMENSIONAL GEOMETRY  
Inventors: Constantin Bulucea and Rebecca Rossen

Dear Paul:

Please prepare a patent application for this invention for filing in the  
United States.

You will note that Constantin Bulucea has not specified his citizenship on  
the Invention Disclosure Form, but has shown his U.S. Resident Alien Number. He  
was born in Romania, but he says he is no longer Romanian.

Your files M-300, M-300/1, M-300/2, and M-584 may relate to this invention.

Very truly yours,

Siliconix incorporated

*Handwritten signature of Lorimer K. Hill*

Lorimer K. Hill  
Patent Coordinator

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Enclosure:

Disclosure of Invention, dtd 11Aug88, 41 pp.

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